I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner of Patents and Trademarks, Alexandria, VA.22313, on June 252004. The applicant and/or attorney requests the date of deposit as the filing date. Depositor: Karen Cinq-Mars

Signature & date)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

e application of

June 252004

Michael P. Belyansky et al.:

Group Art Unit:

Serial No.10/708,430 :

Examiner:

Paula McCray

3/3/2004 Filed:

International Business Machines Corporation

2070 Route 52

Hopewell Junction, NY 12533

TITLE:

Mobility Enhanced CMOS Devises

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to the duty of disclosure set forth in 37 C.F.R. 1.56, and further pursuant to the provisions of 37 C.F.R. 1.97 and 1.98, applicants hereby respectfully submit copies of the non-US patents and publications as listed on Form PTO-1449, attached hereto.

In citing these documents, no representation is made nor intended as to the pertinency or nonpertinency of the art, that better art than that listed is not available, or that other art is not applicable.

No fee is believed to be due for this submission. If any fees are required, however, the Commissioner is hereby authorized to charge such fees to Deposit Account No. 09-0458.

> Respectfully submitted, Michael P. Belyansky, et al.

Registration No. 30,238

Telephone No. 845-894-4633

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Supplemental Form PTO-1449 (Modified)			Attorney Docket No.: FIS920030245US1			Serial No.: 10/708, 430 SIPE			
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT			Applicant:						
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